


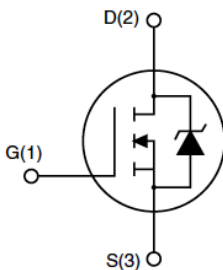


Description

<h3>Features</h3> <ul style="list-style-type: none">● 650V,20A● $R_{DS(ON)} = 0.35\Omega$ (Typ.) @ $V_{GS} = 10V$, $I_D = 10A$● Fast Switching● Improved dv/dt Capability● 100% Avalanche Tested	<h3>Application</h3> <ul style="list-style-type: none">● Switch Mode Power Supply(SMPS)● Uninterruptible Power Supply(UPS)● Power Factor Correction (PFC)		
 <p>TO-247</p>	 <p>TO-3P</p>	 <p>TO-220F</p>	 <p>Schematic Diagram</p>

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Max.		Units
		TO-220F	TO-247/TO-3P	
V_{DSS}	Drain-Source Voltage	650		V
V_{GSS}	Gate-Source Voltage	± 30		V
I_D	Continuous Drain Current	$T_C = 25^\circ\text{C}$	20	A
		$T_C = 100^\circ\text{C}$	13	A
I_{DM}	Pulsed Drain Current ^{note1}	80		A
E_{AS}	Single Pulsed Avalanche Energy ^{note2}	1350		mJ
P_D	Power Dissipation $T_C = 25^\circ\text{C}$	167	416	W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.75	0.3	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	60	60	$^\circ\text{C}/\text{W}$
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +150		$^\circ\text{C}$

Electrical Characteristics ($T_C=25^{\circ}\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristic						
V _{(BR)DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V,I _D =250μA	650	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 650V, V _{GS} = 0V, T _J = 25℃	-	-	1	μA
I _{GSS}	Gate to Body Leakage Current	V _{DS} =0V, V _{GS} = ±30V	-	-	±100	nA
On Characteristics						
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D =250μA	2	3	4	V
R _{DS(on)}	Static Drain-Source on-Resistance note3	V _{GS} =10V, I _D =10A	-	0.35	0.45	Ω
Dynamic Characteristics						
C _{iss}	Input Capacitance	V _{DS} = 25V, V _{GS} = 0V, f = 1.0MHz	-	2978	-	pF
C _{oss}	Output Capacitance		-	291	-	pF
C _{rss}	Reverse Transfer Capacitance		-	40	-	pF
Q _g	Total Gate Charge	V _{DD} = 520V, I _D = 20A, V _{GS} = 10V	-	80	-	nC
Q _{gs}	Gate-Source Charge		-	12	-	nC
Q _{gd}	Gate-Drain(“Miller”) Charge		-	34	-	nC
Switching Characteristics						
t _{d(on)}	Turn-on Delay Time	V _{DD} = 325V, I _D =20A, R _G = 25Ω	-	37	-	ns
t _r	Turn-on Rise Time		-	66	-	ns
t _{d(off)}	Turn-off Delay Time		-	175	-	ns
t _f	Turn-off Fall Time		-	84	-	ns
Drain-Source Diode Characteristics and Maximum Ratings						
I _S	Maximum Continuous Drain to Source Diode Forward Current		-	-	20	A
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	80	A
V _{SD}	Drain to Source Diode Forward Voltage	V _{GS} = 0V, I _{SD} = 20A	-	-	1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} =0V, I _S =20A,	-	450	-	ns
Q _{rr}	Reverse Recovery Charge	di/dt=100A/μs	-	7.1	-	μC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2. $I_{AS} = 16A, V_{DD} = 50V, R_G = 25\Omega$, Starting $T_J = 25^{\circ}\text{C}$

3. Pulse Test: Pulse Width $\leq 350\mu s$, Duty Cycle $\leq 1\%$

Typical Performance Characteristics

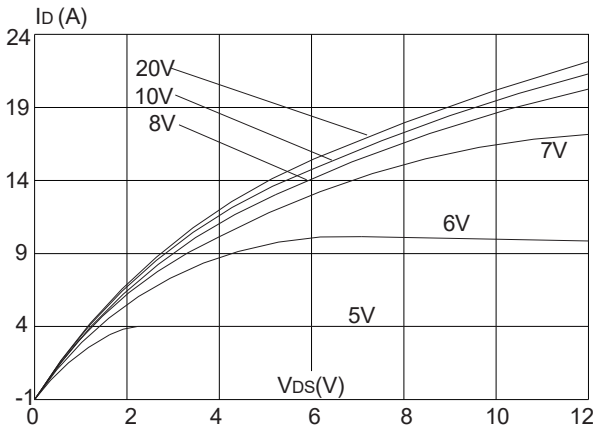
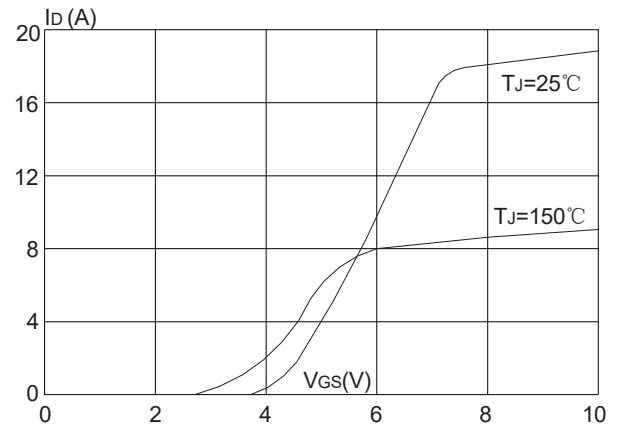
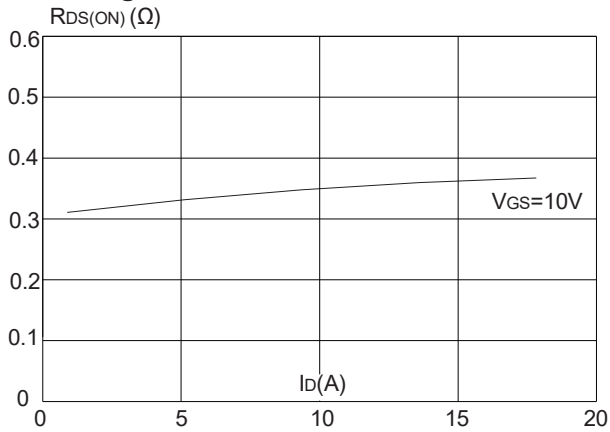
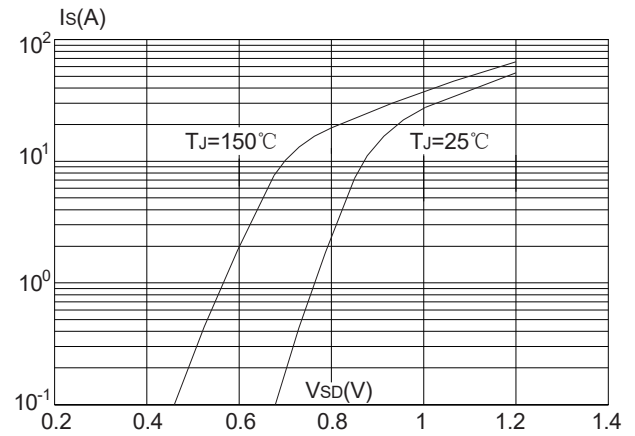
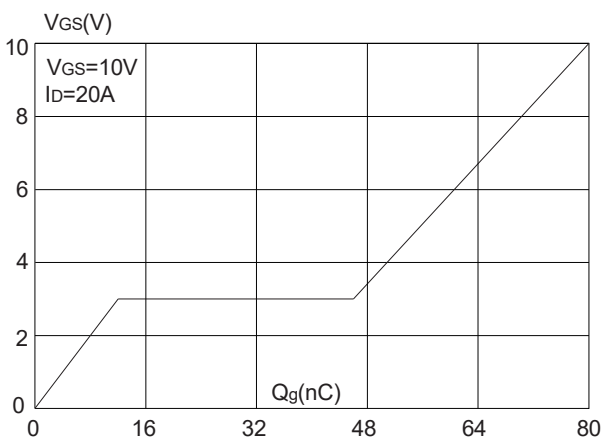
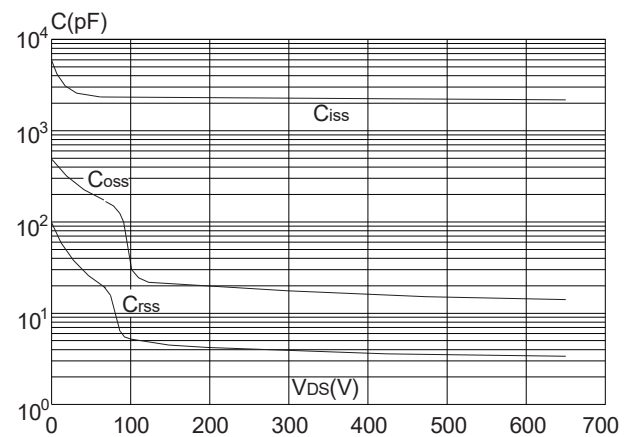
Figure1: Output Characteristics

Figure 2: Typical Transfer Characteristics

Figure 3: On-resistance vs. Drain Current

Figure 4: Body Diode Characteristics

Figure 5: Gate Charge Characteristics

Figure 6: Capacitance Characteristics


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

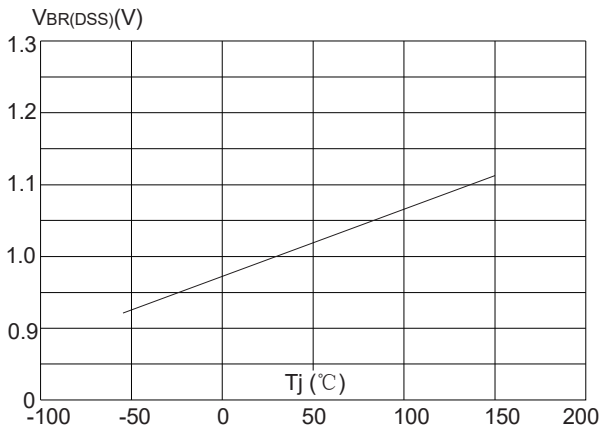


Figure 8: Normalized on Resistance vs. Junction Temperature

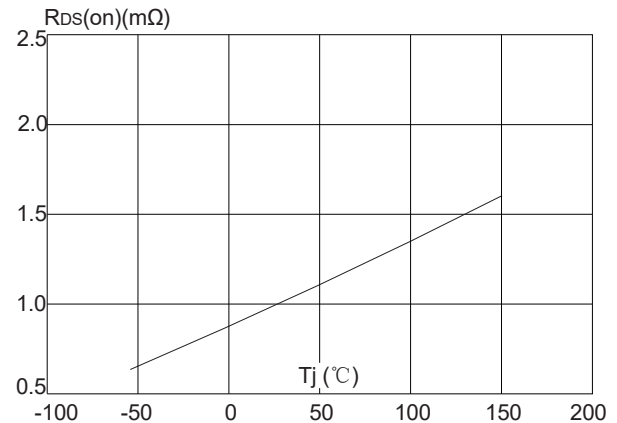


Figure 9: Maximum Safe Operating Area

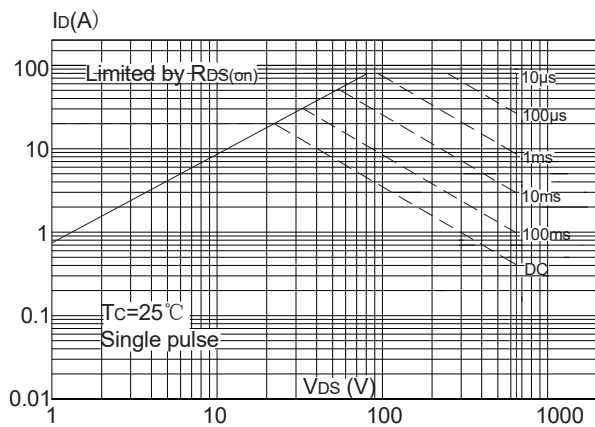


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

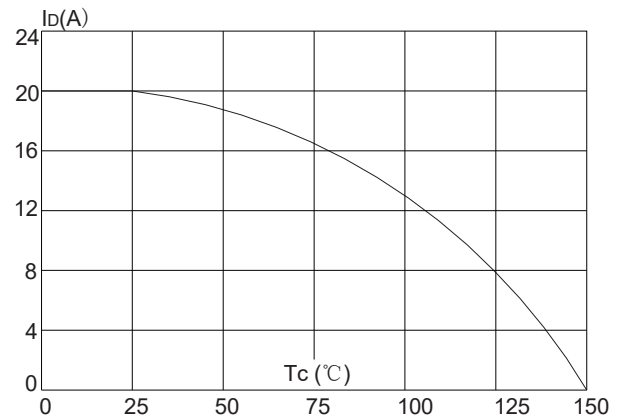


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case (TO-220F)

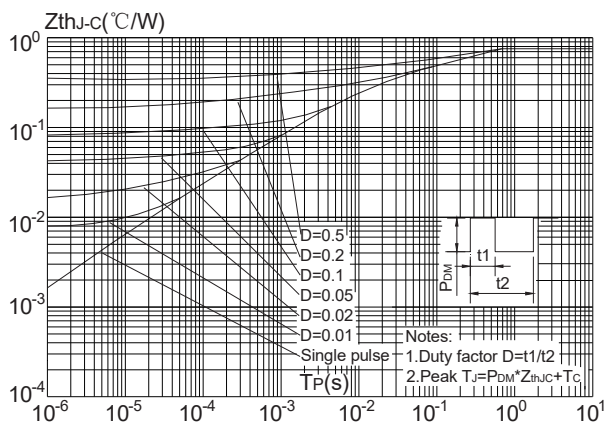
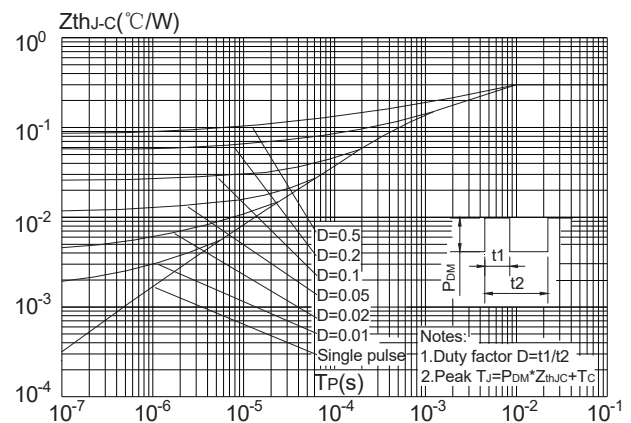
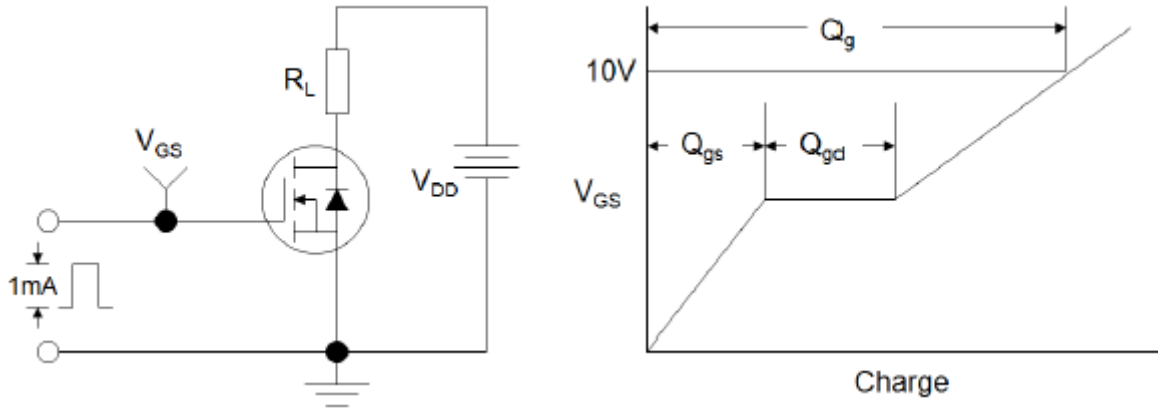
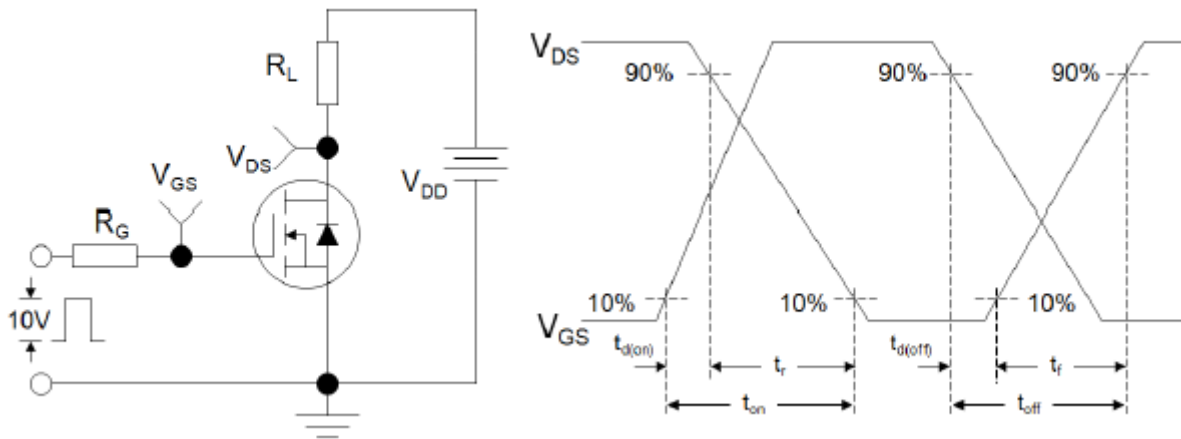
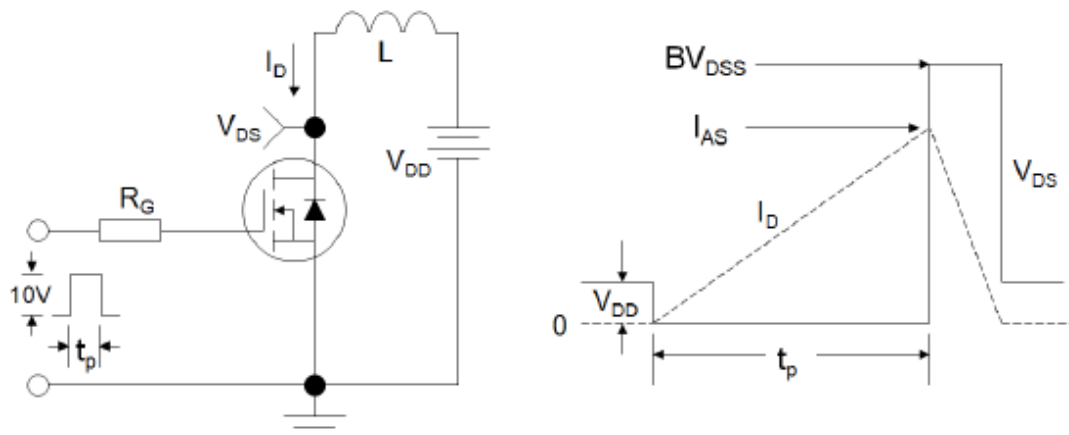


Figure.12: Maximum Effective Transient Thermal Impedance, Junction-to-Case (TO-247, TO-3P)




Figure1:Gate Charge Test Circuit & Waveform

Figure 2: Resistive Switching Test Circuit & Waveforms

Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms

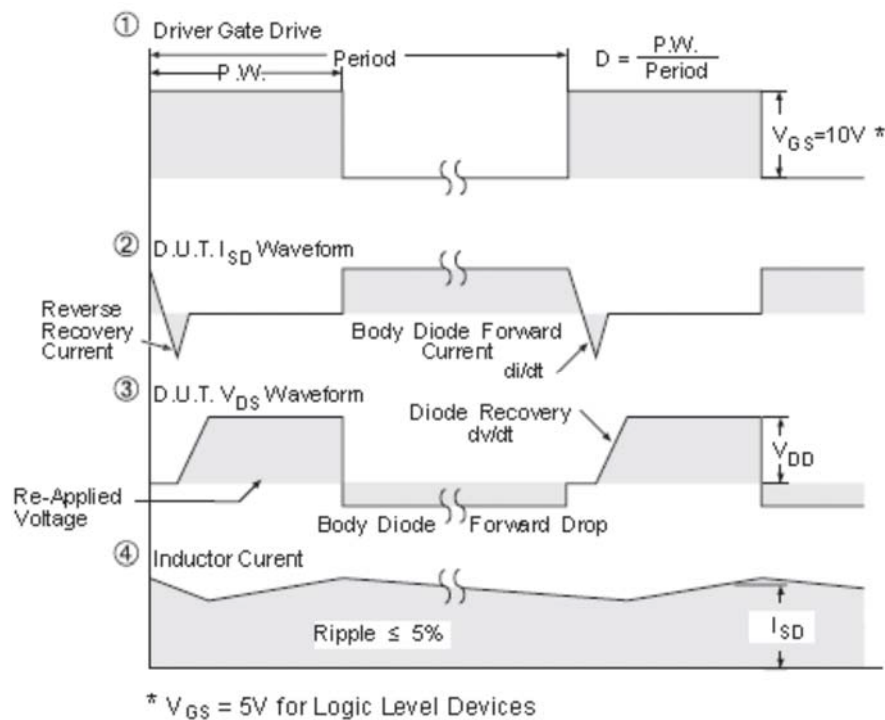
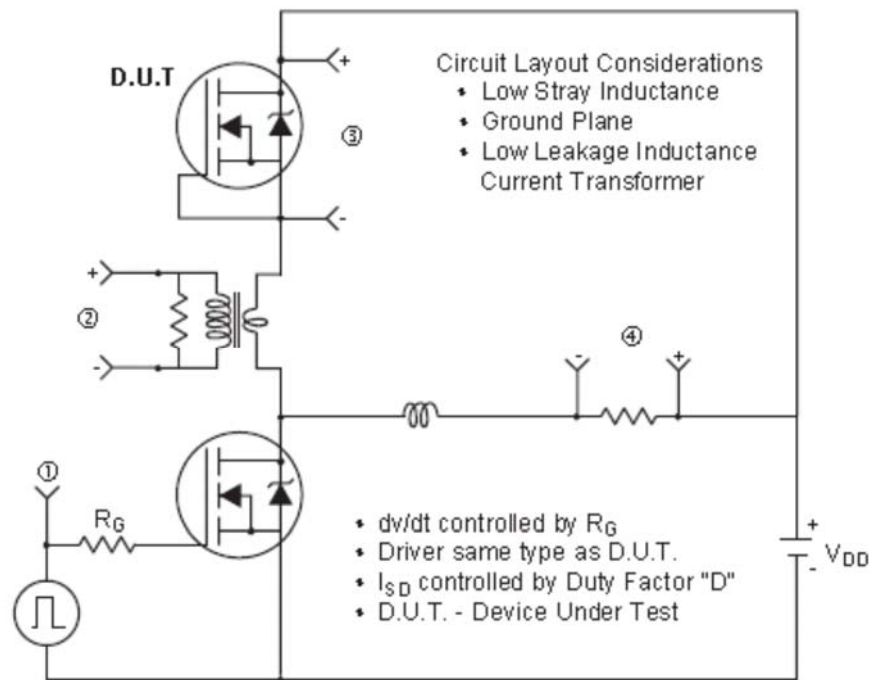


Figure 4: Peak Diode Recovery dv/dt Test Circuit & Waveforms (For N-channel)